TOSHIBA Field Effect Transistor Silicon N-Channel MOS Type (MACH II  $\pi$ -MOS V)

# **TPCS8008-H**

High-Speed Switching Applications Switching Regulator Applications DC/DC Converter Applications

- Low drain-source ON-resistance: RDS (ON) =  $0.48 \Omega$  (typ.)
- High forward transfer admittance:  $|Y_{fs}| = 1.8 \text{ S (typ.)}$
- Low leakage current:  $IDSS = 100 \mu A (max) (VDS = 250 V)$
- Enhancement model:  $V_{th} = 2.0 \sim 4.0 \text{ V}$  ( $V_{DS} = 10 \text{ V}$ ,  $I_{D} = 1 \text{ mA}$ )

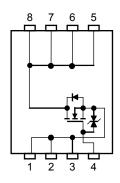
### **Absolute Maximum Ratings (Ta = 25°C)**

Character	istic	Symbol	Rating	Unit
Drain-source voltage		$V_{DSS}$	250	V
Drain-gate voltage ( $R_{GS} = 20 \text{ k}\Omega$ )		$V_{DGR}$	250	V
Gate-source voltage		V <sub>GSS</sub>	±20	V
Danie accessed	DC (Note 1)	I <sub>D</sub>	1.7	Α
Drain current	Pulse (Note 1)	I <sub>DP</sub>	6.8	A
Drain power dissipatio	n (t = 10 s) (Note 2a)	PD	1.5	W
Drain power dissipatio	n (t = 10 s) (Note 2b)	PD	0.6	VV
Single-pulse avalanch	e energy(Note3)	E <sub>AS</sub>	1.7	mJ
Avalanche current		I <sub>AR</sub>	1.7	Α
Repetitive avalanche energy (Note2a, Note 4)		E <sub>AR</sub>	0.15	mJ
Channel temperature		T <sub>ch</sub>	150	°C
Storage temperature range		T <sub>stg</sub>	-55~150	°C

# Unit: mm | 0.525| | 0.65 | 0.25±0.05 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65 | 0.65

Weight: 0.036 g (typ.)

### **Circuit Configuration**



Note: For Notes 1 to 4, refer to the next page.

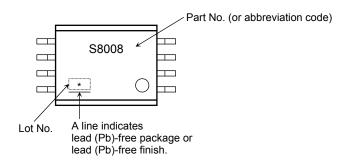
Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

This transistor is an electrostatic-sensitive device. Handle with care.

### **Thermal Characteristics**

Characteristics	Symbol	Max	Unit	
Thermal resistance, channel to ambient (t = 10 s) (Note 2a)	R <sub>th (ch-a)</sub>	83.3	°C/W	
Thermal resistance, channel to ambient (t = 10 s) (Note 2b)	R <sub>th (ch-a)</sub>	208	°C/W	

### Marking (Note 5)

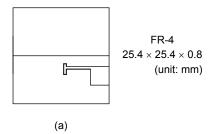


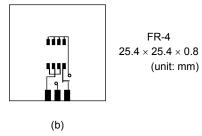
Note 1: The channel temperature should not exceed 150°C during use.

### Note 2:

a) Device mounted on a glass-epoxy board (a)

b) Device mounted on a glass-epoxy board (b)





Note 3:  $V_{DD}$  = 50 V,  $T_{ch}$  = 25°C (initial), L = 1.0 mH,  $R_G$  = 25  $\Omega$ ,  $I_{AR}$  = 1.7 A

Note 4: Repetitive rating: pulse width limited by maximum channel temperature

Note 5: O on the lower right of the marking indicates Pin 1.

\* Weekly code: (Three digits)

Week of manufacture
(01 for first week of year, continuing up to 52 or 53)

Year of manufacture
(The last digit of the calendar year)

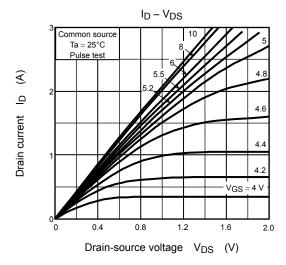
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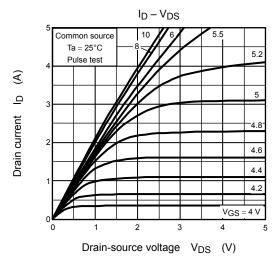
# **Electrical Characteristics (Ta = 25°C)**

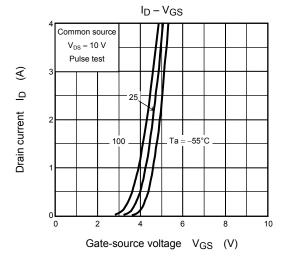
Ch	aracteristic	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cur	rent	I <sub>GSS</sub>	$V_{GS} = \pm 16 \text{ V}, V_{DS} = 0 \text{ V}$	_		±10	μА
Drain cutoff curre	nt	I <sub>DSS</sub>	V <sub>DS</sub> = 150 V, V <sub>GS</sub> = 0 V	_	_	100	μА
		V <sub>(BR) DSS</sub>	$I_D = 10 \text{ mA}, V_{GS} = 0 \text{ V}$	250	_	_	
Drain-source breakdown voltage		V <sub>(BR) DSX</sub>	$I_D = 10 \text{ mA}, V_{GS} = -5 \text{ V}$	250	_	_	٧
		V <sub>(BR) DSX</sub>	$I_D = 10 \text{ mA}, V_{GS} = -20 \text{ V}$	200	_	_	
Gate threshold vo	oltage	V <sub>th</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 1 mA	2.0	_	4.0	V
Drain-source ON-resistance		R <sub>DS</sub> (ON)	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 0.8 A	_	0.48	0.58	Ω
Forward transfer admittance		Y <sub>fs</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 0.8 A	0.8	1.8	_	S
Input capacitance	)	C <sub>iss</sub>		_	600	_	pF
Reverse transfer capacitance		C <sub>rss</sub>	$V_{DS} = 10 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	_	20	_	pF
Output capacitance		C <sub>oss</sub>			220	_	pF
Switching time	Rise time	t <sub>r</sub>	V <sub>GS</sub> 10 V		35	_	
	Turn-on time	t <sub>on</sub>		_	95	_	
	Fall time	t <sub>f</sub>		_	20	_	ns
	Turn-off time	t <sub>off</sub>	Duty ≦ 1%, t <sub>w</sub> = 10 μs		120	_	
Total gate charge (gate-source plus gate-drain)		Qg	$V_{DD} \simeq 200V, V_{GS} = 10 V,$ $I_{D} = 1.7 A$		10		nC
Gate-source charge		Q <sub>gs</sub>		_	7.5	_	nC
Gate-drain ("Miller") charge		Q <sub>gd</sub>			2.5	_	nC
Gate switch charge		Q <sub>sw</sub>		_	3.3	_	nC

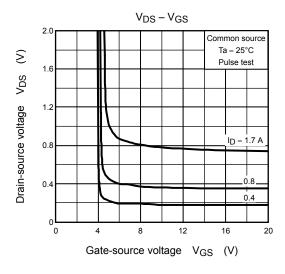
# Source-Drain Ratings and Characteristics (Ta = 25°C)

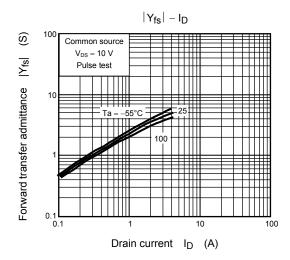
Characteristic		Symbol	Test Condition	Min	Тур.	Max	Unit
Drain reverse current (pulse)	(Note 1)	I <sub>DRP</sub>	_	_	_	6.8	Α
Forward voltage (diode)		V <sub>DSF</sub>	I <sub>DR</sub> = 1.7 A, V <sub>GS</sub> = 0 V	_	_	-2.0	V

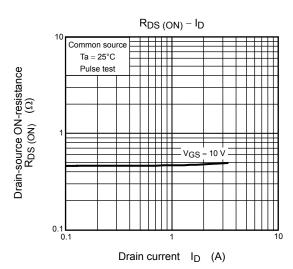


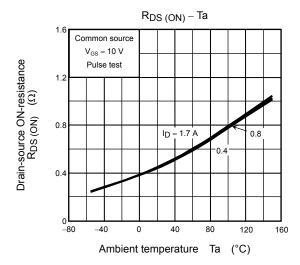


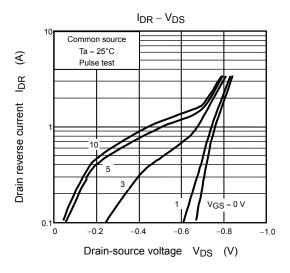


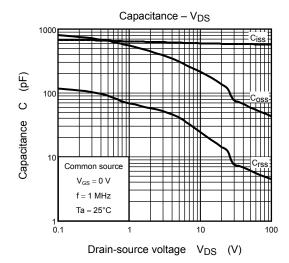


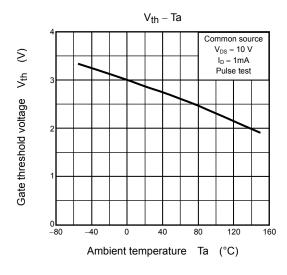


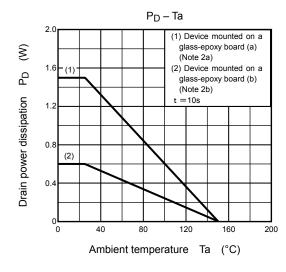


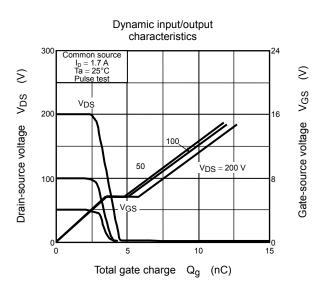




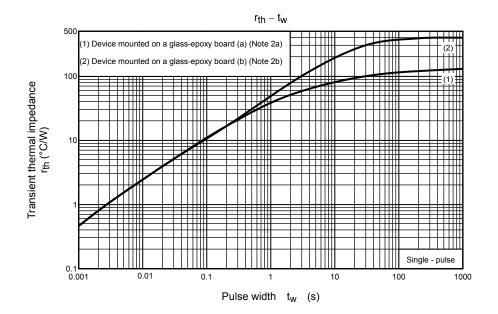


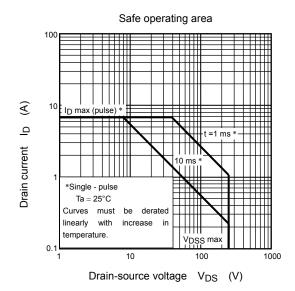






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